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**INFORMATION DISCLOSURE
STATEMENT BY APPLICANT**

(use as many sheets as necessary)

Complete if Known

Application Number	10/731,089
Filing Date	December 10, 2003
First Named Inventor	Shinya SASAGAWA et al.
Art Unit	1765
Examiner Name	Not Assigned Yet
Attorney Docket Number	740756-2676

Sheet

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U.S. PATENT DOCUMENTS

Examiner Initials ¹	Cite No. ²	U.S. Patent Document	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Number - Kind Code ³ (if known)			
MA	1	US-6,596,571 B2	07/22/2003	Arao et al.	
MA	2	US-6,646,287 B1	11/11/2003	Ono et al.	
MA	3	US-6,706,544 B2	03/16/2004	Yamazaki et al.	
MA	4	US-6,872,604 B2	03/29/2005	Yamazaki et al.	
MA	5	US-6,933,184 B2	08/23/2005	Arao et al.	
MA	6	US-2001/0041392 A1	11/15/2001	Suzawa et al.	
MA	7	US-2001/0048408 A1	12/06/2001	Koyama et al.	
MA	8	US-2002/0102776 A1	08/01/2002	Yamazaki et al.	
MA	9	US-2002/0163049 A1	11/07/2002	Yamazaki et al.	
MA	10	US-2003/0020118 A1	01/30/2003	Kajiware et al.	
MA	11	US-2003/0062524 A1	04/03/2003	Kimura	
MA	12	US-2003/0100151 A1	05/29/2003	Okamoto	
MA	13	US-2004/0140472 A1	07/22/2004	Fujimoto et al.	
MA	14	US-2004/0171242 A1	09/02/2004	Monoe et al.	
MA	15	US-2004/0209409 A1	10/21/2004	Monoe et al.	

OTHER PRIOR ART - NON PATENT LITERATURE DOCUMENTS

Examiner Initials ¹	Cite No. ²	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T ³
MA	16	Y. MISHIMA et al.; "Improved Lifetime of Poly-Si TFTs With a Self-Aligned Gate-Overlapped LDD Structure"; IEEE TRANSACTIONS ON ELECTRON DEVICES; 06/01/2002; Vol. 49; No. 6; PP. 981-985	
MA	17	K. OHGATA et al.; "A New Dopant Activation Technique for Poly-Si TFTs With a Self-Aligned Gate-Overlapped LDD Structure"; IEDM: TECHNICAL DIGEST OF INTERNATIONAL DEVICES MEETING; 12/10/2000; PP. 205-208.	

Examiner Signature	/Maki Angadi/	Date Considered	09/08/2006
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